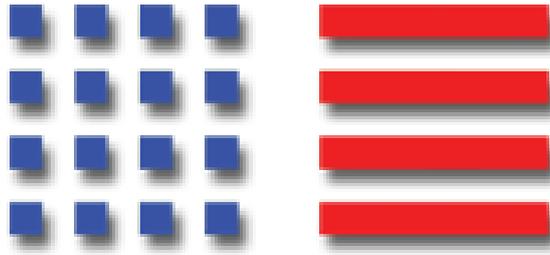


6th Belle II PXD/SVD workshop and 17th International Workshop on  
DEPFET Detectors and Applications



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## Summary of DEPFET characteristics measured on beam tests

*Thursday, 2 October 2014 14:30 (20 minutes)*

**Presenter:** SCHWENKER, Benjamin (Göttingen)

**Session Classification:** Parallel